Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	nt under	
10/790,718	CHANG, CHEN-CHUNG		
Examiner	Art Unit		
EDMUND H. LEE	1732		

SEARCHED					
Class	Subclass	Date	Examiner		
264	263	6/13/2006	EHL		
	250				
	261				
	328.1				
	259				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
264	263,261	6/13/2006	EHL		
	328.1				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	6/13/2006	EHL	
INVENTOR			